

The RCA CD54/74AC651 and CD54/74AC652 and the CD54/74ACT651 and CD54/74ACT652 3-state, octal-bus transceiver/registers use the RCA ADVANCED CMOS technology. The CD54/74AC651 and CD54/74ACT651 have inverting outputs. The CD54/74AC652 and CD54/74ACT652 have non-inverting outputs. These devices consist of bus transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Output Enables OEAB and OEBA are provided to control the transceiver functions. SAB and SBA control pins are provided to select whether real-time or stored data is transferred. The circuitry used for select control will eliminate the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. A LOW input level selects real-time data, and a HIGH selects stored data. The following examples demonstrate the four fundamental busmanagement functions that can be performed with the octal-bus transceivers and registers.

Data on the A or B data bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock pins (CAB or CBA) regardless of the select or enable control pins. When SAB and SBA are in the real-time transfer mode, it is also possible to store data without using the internal D-type flip-flops by simultaneously enabling OE_{AB} and OE_{BA} . In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines will remain at its last state.

The CD74AC/ACT651 and CD74AC/ACT652 are supplied in 24-lead dual-in-line narrow-body plastic packages (EN suffix) and in 24-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Commercial (0 to 70°C); Industrial (-40 to +85°C); and Extended Industrial/Military (-55 to +125°C).

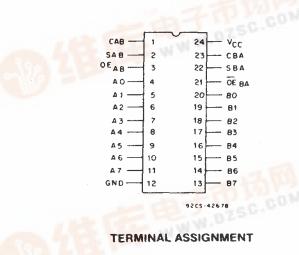
The CD54AC/ACT651 and CD54AC/ACT652, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

PDF

Family Features:

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST*/AS/S with significantly
- reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply
- ± 24-mA output drive current
 Fanout to 15 FAST* ICs
 - Drives 50-ohm transmission lines

*FAST is a Registered Trademark of Fairchild Semiconductor Corp.



CD54/74AC651, CD54/74AC652

CD54/74ACT651, CD54/74ACT652

	INPUTS			INPUTS			A I/O	OPERATION (DR FUNCTION
OEAB	OE _{8A}	CAB	CBA	SAB	SBA	A0 THRU A7	B0 THRU B7	651	652
L	н	H or L	H or L	X	×	Input	Innut	Isolation *	Isolation*
L	н			Х	<u> </u>	mput	Input -	Store A and B Data	Store A and B Data
х	н		H or L	X	х	Input	Unspecified [†]	Store A, Hold B	Store A, Hold B
н	Н		<u></u>	x‡	X	Input	Output	Store A in both registers	Store A in both registers
L	x	H or L		Х	х	Unspecified [†]	Input	Hold A, Store B	Hold, A Store B
L	L			Х	x‡	Output	Input	Store B in both registers	Store B in both registers
L	L	X	х	Х	L	0.1.1		Real-Time B Data to A Bus	Real-Time B Data to A Bus
L	L	X	H or L	X	н	Output	Input	Stored B Data to A Bus	Stored B Data to A Bus
н	н	X	X	L	X		<u></u>	Real-Time A Data to B Bus	Real-Time A Data to B Bus
н	H ·	H or L	х	н	х	Input	Output	Stored A Data to B Bus	Stored A Data to B Bus
н		HorL	Цан	н	н	<u> </u>	<u> </u>	Stored A Data to B Bus and	Stored A Data to B Bus
	L.	TIOL	- H ULL	r1	LI	Output	Output	Stored B Data to A bus	Stored B Data to A Bus

FUNCTION TABLE

* To prevent excess currents in the High-Z (isolation) modes, all I/O terminals should be terminated with 10kΩ to 1MΩ resistors.

† The data output functions may be enabled or disabled by various signals at the OE_{AB} or OE_{BA} inputs. Data input functions are always enabled, i.e., data at the bus pins will be stored on every low-to-high transition on the clock inputs.

‡ Select control = L: clocks can occur simultaneously.

Select control = H: clocks must be staggered in order to load both registers.

MAXIMUM RATINGS, Absolute-Maximum Values:

$ \begin{array}{llllllllllllllllllllllllllllllllllll$
POWER DISSIPATION PER PACKAGE (Po):
For T _A = -55 to +100°C (PACKAGE TYPE E)
For $I_A = \pm 100$ to ± 125 °C (PACKAGE TYPE E) Derate Linearly at 8 mW/°C to 300 mW
For T _A = -55 to +70°C (PACKAGE TYPE M)
For T _A = +70 to +125°C (PACKAGE TYPE M) Derate Linearly at 6 mW/°C to 70 mW
OPERATING-TEMPERATURE RANGE (T _A)
STORAGE TEMPERATURE (T _{stg})65 to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16 \pm 1/32 in. (1.59 \pm 0.79 mm) from case for 10 s maximum
Unit inserted into PC board min. thickness 1/16 in. (1.59 mm) with solder contacting lead tips only+300°C
For up to 4 outputs per device; add \pm 25 mA for each additional output.

RECOMMENDED OPERATING CONDITIONS:

For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTICS	LIN		
CHARACTERISTICS	MIN.	MAX.	UNITS
Supply-Voltage Range, Vcc*:			
(For $T_A = Full Package-Temperature Range)$			
AC Types	1.5	5.5	V
ACT Types	4.5	5.5	V V
DC Input or Output Voltage, V _I , V ₀	0	Vcc	V
Operating Temperature, T _A	-55	+125	°C
Input Rise and Fall Slew Rate, dt/dv			1
at 1.5 V to 3 V (AC Types)	0	50	ns/V
at 3.6 V to 5.5 V (AC Types)	0	20	ns/V
at 4.5 V to 5.5 V (ACT Types)	0	10	ns/V

*Unless otherwise specified, all voltages are referenced to ground.

Technical Data CD54/74AC651, CD54/74AC652 CD54/74ACT651, CD54/74ACT652

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STATIC ELECTRICAL CHARACTERISTICS: AC Series

						AMBIEN	Г ТЕМРЕ	RATURE	E (T _A) - ° (C .]			
CHARACTERISTICS		TEST CO	NDITIONS	V _{cc}	+	25	-40't	o +85	-55 to	o +125	UNITS			
		V, (V).	l _o (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.]			
High-Level Input Voltage	VIH			1.5 3 5.5	1.2 2.1 3.85	=	1.2 2.1 3.85	-	1.2 2.1 3.85	-	v			
Low-Level Input Voltage	V _{IL}			1.5 3 5.5		0.3 0.9 1.65		0.3 0.9 1.65	-	0.3 0.9 1.65	v			
High-Level Output	~~	· · · ·	-0.05	1.5	1.4	<u> </u>	1.4	-	1.4	-	1			
Voltage	V _{он}	VIH	-0.05	3	2.9	-	2.9	-	2.9]			
,		or	-0.05	4.5	4.4		4.4		4.4	·]			
		ViL	-4	3	2.58	_	2.48	-	2.4] v			
			-24	4.5	3.94	_	3.8		3.7] .			
		#, * {	-75	5.5			3.85]			
		("· ł	-50	5.5		_		-	3.85		1			
Low-Level Output	Vol		0.05	1.5		0.1		0.1		0.1				
Voltage		Vol	VOL	Vн	0.05	3	_	0.1		0.1		0.1		
		or	0.05	4.5	-	0.1	—	0.1		0.1]			
		ViL	12	3		0.36		0.44		0.5] V			
				24	4.5		0.36	—	0.44		0.5]		
							#, * {	75	5.5	-	-	-	1.65	
		"• _ ₹	50	5.5	-		·			1.65]			
Input Leakage Current	h	V _{cc} or GND		5.5		±0.1		±1	-	±1	μA			
3-State Leakage Current	loz	V _{IH} or V _{IL} V _O = V _{cc} or GND		5.5		±0.5		±5		<u>+</u> 10	μA			
Quiescent Supply Current, MSI	l _{cc}	V _{cc} or GND	0	5.5		8		80		160	μA			

#Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

_ Technical Data

CD54/74AC651, CD54/74AC652 CD54/74ACT651, CD54/74ACT652

STATIC ELECTRICAL CHARACTERISTICS: ACT Series

						AMBIEN		RATURE	E (T _A) - °	С	
CHARACTERISTICS		TEST CONDITIONS		V _{cc}	+25		-40 t	o +85	-55 to +125		UNITS
		V, (V)	l _o (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	•
High-Level Input Voltage	ViH			4.5 to 5.5	2	_	2	·	2		v
Low-Level Input Voltage	ViL			4.5 to 5.5		0.8		0.8	-	0.8	v
High-Level Output		ViH	-0.05	4.5	4.4	-	4.4		4.4		
Voltage	Vон	or Vit	-24	4.5	3.94		3.8		3.7	[]
		#, * {	-75	5.5			3.85				1 V
		<u>"' (</u>	-50	5.5					3.85		1
Low-Level Output		ViH	0.05	4.5	—	0.1	-	0.1	-	0.1	
Voltage	Vol	or V _{IL}	24	4.5	-	0.36	_	0.44		0.5	1 v
		#, * \$	75	5.5		-		1.65		_	
		" ^{, "} {	50	5.5	_				-	1.65	1
Input Leakage Current	h	V _{cc} or GND		5.5	_	±0.1	_	±1	_	±1	μA
3-State Leakage Current	loz	Vін or ViL Vo= Vcc or GND		5.5	_	±0.5	_	±5	_	±10	μΑ
Quiescent Supply Current, MSI	łcc	V _{cc} or GND	0	5.5		8	_	80	_	160	μA
Additional Quiescent Su Current per Input Pin TTL Inputs High 1 Unit Load	upply ∆l _{cc}	V _{cc} -2.1		4.5 to 5.5		2.4		2.8		3	mA

#Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation. * Test verifies a minimum 50-ohm transmission-line-drive capability at +85° C, 75 ohms at +125° C.

ACT INPUT LOADING TABLE

INPUT	UNIT LOAD*
CAB, CBA	1.25
SAB, SBA	1.2
OEAB	0.67
ÖE BA	1.17
An, Bn	0.4

*Unit load is ΔI_{cc} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25°C.

Technical Data __ CD54/74AC651, CD54/74AC652 CD54/74ACT651, CD54/74ACT652

PREREQUISITE FOR SWITCHING: AC Series

			AMBI	ENT TEMPE	RATURE (T			
CHARACTERISTICS	SYMBOL	V _{cc} (V)	-40 (lo +85	-55 to	+125	UNITS	
	· · ·	(*)	MIN.	MAX.	MIN.	MAX.] .	
Max. Frequency	fmax	1.5 3.3* 5†	11 101 143		10 89 125		MHz	
Setup Time Data to Clock	tsu	1.5 3.3 5	27 3.1 2.2	-	31 3.5 2.5		ns	
Hold Time Data to Clock	t _H	1.5 3.3 5	2 2 2		2 2 2		ns	
Clock Pulse Data to Clock	tw	1.5 3.3 5	44 4.9 3.5	-	50 5.6 4	-	ns	

*3.3 V: min. is @ 3 V

†5 V; min. is @ 4.5 V

SWITCHING CHARACTERISTICS: AC Series; t,, tr = 3 ns, CL = 50 pF

		,	AMBI	AMBIENT TEMPERATURE (TA) - °C					
CHARACTERISTICS	SYMBOL	V _{cc}	-40 t	o +85	-55 t	o +125			
		(V)	MIN.	MAX.	MIN.	MAX.]		
Propagation Delays:			+	·		1	1		
Store A Data to B Bus		1.5	-	154	_	169	1		
Store B Data to A Bus	t _{PLH}	3.3*	4.8	17.1	4.7	18.9	ns		
652	tрн⊾	5†	3.5	12.3	3.4	13.5			
Store A Data to B Bus		1.5		154		169	†		
Store B Data to A Bus	t _{РLН}	3.3	4.8	17.1	4.7	18.9	ns		
651	tры	5	3.5	12.3	3.4	13.5			
A Data to B Bus		1.5		125		138	1		
B Data to A Bus	t _{PLH}	3.3	4	14	3.9	15.4	ns		
652	t _{PHL}	5	2.8	10	2.8	11			
A Data to B Bus		1.5		125	_	138	<u>+</u> -		
B Data to A Bus	T PLH	3.3	4	14	3.9	15.4	ns		
651	1 _{PHL}	5	2.8	10	2.8	11			
Select to Data		1.5		136		150	+		
652	(PLH	3.3	4.3	15.3	4.2	16.8	ns		
	t _{PHL}	5	3.1	10.9	3	12			
Select to Data		1.5		136		150	+		
651	t _{PLH}	3.3	4.3	15.3	4.2	16.8	ns		
	tphi_	5	3.1	10.9	3	12			
3-State Enabling/	tezl		1				<u> </u>		
Disabling Time	tezh	1.5	-	154	_	169	1		
Bus to Output or	teuz	3.3	5.2	18.4	5.1	20.2	ns		
Register to Output	1PHZ	5	3.5	12.3	3.4	13.5	1		
Power Dissipation Capacitance	CPD§		150	Тур.	150	Тур.	pF		
Min. (Valley)	Voh				L	<u> </u>	<u>↓</u>		
During Switching of	Vону								
Other Outputs (Output	See	5		4 Typ. (@ 25° C		V V		
Under Test Not	Fig. 1	_	1						
Switching)	J						· ·		
Max. (Peak)	Vol		1			_,, ·	1		
During Switching of	Vole								
Other Outputs (Output	See	5	1	1 Typ. (@ 25° C		V		
Under Test Not	Fig. 1				~				
Switching)	5		1						
Input Capacitance	C,		-	10		10	pF		
3-State Output Capacitance	Co			15		15	pF		
3 V: min. is @ 3.6 V		s used to d	etermine the	dynamic po	wer consu	motion per	nackage		

max. is @ 3 V 15 V: min. is @ 5.5 V

max. is @ 4.5 V

 $f_o =$ output frequency

 C_L = output load capacitance supply voltage V

____ Technical Data

CD54/74AC651, CD54/74AC652 CD54/74ACT651, CD54/74ACT652

PREREQUISITE FOR SWITCHING: ACT Series

			AMBI					
CHARACTERISTICS	SYMBOL	V _{cc} (V)	-40 to +85		-55 to +125			
		(*)	MIN.	MAX.	MIN.	MAX.		
Max. Frequency	fmax	5*	125		110	· _	MHz	
Setup Time Data to Clock	tsu	5	2.2		2.5	-	ns	
Hold Time Data to Clock	t _H	5	2	-	2	_	ns	
Clock Pulse Width	tw	5	3.9	_	4.5	—	ns	

*5 V: min. is @ 4.5 V

<u>}-</u>

SWITCHING CHARACTERISTICS: ACT Series; t, t = 3 ns, CL = 50 pF

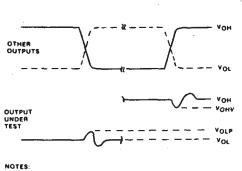
			AMB	AMBIENT TEMPERATURE (TA) - °C				
CHARACTERISTICS	SYMBOL	V _{cc}	-40	to +85	-55 t	o +125		
		(V)	MIN.	MAX.	MIN.	MAX.		
Propagation Delays: Store A Data to B Bus Store B Data to A Bus 652	t _{РLH} t _{PHL}	5*	4	14.1	3.9	15.5	ns	
Store Ā Data to B Bus Store B Data to A Bus 651	t _{РLH} t _{PHL}	5	4	14.1	3.9	15.5	ns	
A Data to B Bus B Data to A Bus 652	tр _{LH} t _{PHL}	5	3.2	11.4	3.1	12.5	ns	
Ā Data to B Bus B Data to A Bus 651	tецн tенц	5	3.2	11.4	3.1	12.5	ns	
Select to Data 652	t _{РСН} t _{РНL}	5	3.7	13.2	3.6	14.5	ns	
Select to Data 651	t _{PLH} t _{PHL}	5	4	14.1	3.9	15.5	ns	
3-State Enabling/ Disabling Time Bus to Output or Register to Output	tpzi tpzh tplz tplz tphz	5	4	14.1	3.9	15.5	ns	
Power Dissipation Capacitance	CPD§		150	Тур.	150 Typ.		pF	
Min. (Valley) During Switching of Other Outputs (Output Under Test Not Switching)	V _{OH} Voнv See Fig. 1	5	4 Typ. @ 25°C		Ĩ	v		
Max. (Peak) During Switching of Other Outputs (Output Under Test Not Switching)	V _{OL} Volp See Fig. 1	5	1 Тур. @		<u>а</u> 25°С		v	
Input Capacitance	C ₁			10		10	p۴	
3-State Output Capacitance	Co	_		15	_	15	рF	

*5 V: min. is @ 5.5 V max. is @ 4.5 V $\label{eq:power} \begin{array}{l} \label{eq:power} \$C_{PD} \text{ is used to determine the dynamic power consumption, per package} \\ P_D \equiv V_{CC}^2 \, C_{PD} \, f_i + \Sigma \, V_{CC}^2 C_L f_0 + V_{CC} \Delta I_{CC} \, \text{where} \quad f_i \approx \text{input frequency} \end{array}$

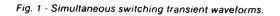
 $f_o =$ output frequency

 $C_L =$ output load capacitance $V_{CC} =$ supply voltage.

Technical Data CD54/74AC651, CD54/74AC652 CD54/74ACT651, CD54/74ACT652



- NOTES: 1. VGNY AND VOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST. 2. INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS: PRR (1 MHz, t, 3 no, t) (1 3 ns, SKEW 1 ns. 3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED. IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 # CAPACITOR. SCOPE AND PROBES REQUIRE 700-MHz BANDWIDTH.
- - 9205-42406



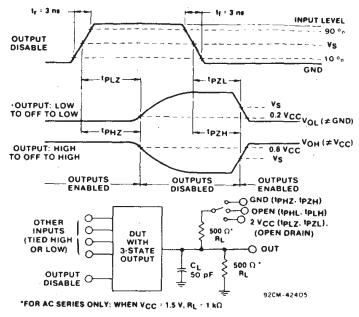
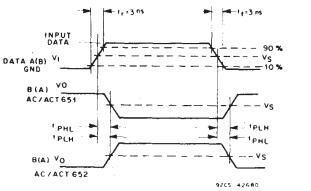
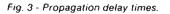


Fig. 2 - Three-state propagation delay waveforms and test circuit.





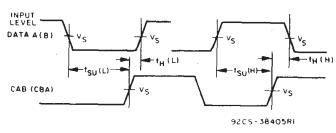


Fig. 4 - Data setup and hold times.

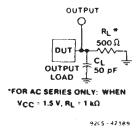


Fig. 5 - Test circuit.

	CD54/74AC	CD54/74ACT
Input Level	Vcc	3 V
Input Switching Voltage, Vs	0.5 V _{cc}	1.5 V
Output Switching Voltage, Vs	0.5 V _{cc}	0.5 Vcc

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